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TRANSMITTAL FORM (to be used for all correspondence after initial filing)	Application Number	10/636,038
	Filing Date	August 6, 2003
	First Named Inventor	Gurtej Sandhu
	Art Unit	2812
	Examiner Name	Unkonwn
Total Number of Pages in This Submission	Attorney Docket Number	MI22-2194

ENCLOSURES (Check all that apply)		
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Remarks <div style="text-align: center; font-size: 2em;">EV372467864</div>		

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT	
Firm or Individual	Mark S. Matkin, Reg No. 32,268 Wells St. John, P.S.
Signature	
Date	11/8/04

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/636,038
Filing Date August 6, 2003
Inventor Gurtej Sandhu
Assignee Micron Technology, Inc.
Group Art Unit 2812
Examiner Unknown
Attorney's Docket No. MI22-2194
Title: Methods of Forming Material on a Substrate and a Method of Forming a
Field Effect Transistor Gate Oxide on a Substrate

INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

EV372467864

From: (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
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Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449 and copies of which are attached.

This Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing of a first Office Action, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No.

23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

Citations of these references are respectfully requested.

Respectfully submitted,

Dated: 11-8-04

By:

A handwritten signature in black ink, appearing to read 'Mark S. Matkin', is written over a horizontal line.

Mark S. Matkin

Reg. No. 32,268

Form PTO-149

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT
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ATTY. DOCKET NO.
MI22-2194

SERIAL NO.
10/636,038

APPLICANT
Gurtej Sandhu

FILING DATE
August 6, 2003

GROUP
2812

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	6,495,436	12/17/2002	Ahn et al.			
AB	6,762,114	7/13/2004	Chambers			
AC	6,717,226	4/6/2004	Hedge et al.			
AD	6,608,378	8/19/2003	Ahn et al.			
AE	6,579,767	6/17/2003	Park et al.			
AF	6,524,918	2/25/2003	Park et al.			
AG	2004/0023462	2/5/2004	Rotondaro et al.			
AH	2003/0232506	12/18/2003	Metzner et al.			
AI	2001/0029092	10/11/2003	Park et al.			
AJ	2001/0024860	9/27/2001	Park et al.			
AK						
AL						

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM							
AN							
AO							
AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR	"Surface preparation and post thermal treatment effects on interface properties of thin Al_2O_3 films deposited by ALD;" Chang et al.; Microelectronic Engineering 72, 2004; pp. 326-331.
AS	"Effect Purge time on the properties of HfO_2 films prepared by atomic layer deposition;" Kawahara et al.; IEEE Transactions on Electronics; Vol. E87-C, No. 1; January 2004; pp. 2-8.
AT	"High-k materials for advanced gate stack dielectrics: a comparison of ALCVD and MOCVD as deposition technologies;" Caymax et al.; CMOS Front-End materials and Process Technology Symposium (Mater. Res. Soc. Symposium Proceedings Vol. 765); April 22-24, 2003; 47-58

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2194		SERIAL NO. 10/636,038	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Gurtej Sandhu			
				FILING DATE August 6, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		"Effect of Hf sources, oxidizing agents, and NH ₃ /Ar plasma on the properties of HfAlO _x films prepared by atomic layer deposition;" Kawahara et al.; Japanese Journal of Applied Physics, Vol. 43, No. 7A; July 2004; pp. 4129-4134.				
	AS		"Characterization of ultra-thin HfO ₂ gate oxide prepared by using atomic layer deposition;" Tacho et al.; Journal of the Korean Physical Society, Vol. 42, No. 2; February 2003; pp. 272-275.				
	AT						
EXAMINER		DATE CONSIDERED					
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							